

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/567,883	STEIN ET AL.	
Examiner		Art Unit		Page 1 of 1
FEI FEI YEUNG LOPEZ		2826		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,397,920	03-1995	Tran, Nang T.	257/749
*	B	US-5,861,636	01-1999	Dutta et al.	257/91
*	C	US-5,889,295	03-1999	Rennie et al.	257/96
*	D	US-2002/0137244	09-2002	Chen et al.	438/22
*	E	US-WO/2002/061855	08-2002	Noto et al	H01L 33/00
*	F	US-2003/0001249	01-2003	Shimanuki, Yoshihiko	257/678
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.